

The working group met on Monday, October 13, at 8:00AM.

Patents:

IEEE-SA rules on Patents were reviewed prior to further discussions. The slides of the IEEE-SA Patents Slide Set dated 25-March-2008 were shown. The WG attendees were advised:

- To avoid prohibited discussion topics and object immediately if discussions move into prohibited discussion topics.
- The IEEE's patent policy is consistent with the ANSI patent policy and is described in Clause 6 of the IEEE-SA Standards Board Bylaws;
- Early identification of patent claims which may be essential for the use of standards under development is encouraged;
- There may be Essential Patent Claims of which the IEEE is not aware. Additionally, neither the IEEE, the WG, nor the WG chair can ensure the accuracy or completeness of any assurance or whether any such assurance is, in fact, of a Patent Claim that is essential for the use of the standard under development.

The participants were provided an opportunity to identify patent claim(s)/patent application claim(s) and/or the holder of patent claim(s)/patent application claim(s) that the participant believes may be essential for the use of the standard which will result from the activity of the WG.

No responses were received during the meeting regarding patent claim(s)/patent application claim(s) and/or the holder of the patent claim(s)/patent application claim(s) that were identified (if any) and by whom.

General:

The PAR for this project was approved by IEEE-SA in 26-Sept-2008.

Attendance included 11 WG (of 18) members (6 excused by E-Mail or due to simultaneous meetings, 1 absent) and 15 guests. Attendance is as shown below:

Members	Members	Members	Guests	Guests
C. Ball (E)	D. Lemmerman (P)	R. Puckett (E)	W. Cheng (P)	G. Schoonenberg(P)
P. Barnhart (P)	A. Livshitz (P)	C. Schneider (P)	T. Esco (P)	A. Storms (P)
E. Byron (A)	D. Mazumdar (P)	J. Smith (P)	M. Flack (P)	D. Smith (P)
P. Dwyer (E)	A. Morgan (E)	C. Taylor (P)	D. Groves (P)	J. Toney (P)
D. Gohil (E)	T. Olsen (P)	M. Wactor (P)	H. Josten (P)	T. Schneider (P)
N. Gunderson (E)	M Orosz (P)	J. Zawadzki (P)	F. Mayle (P)	T. Williams (P)
R. Hartzel (P)			D. Mohla (P)	M. Wong (P)
			E. Peters (P)	

P = present, E = excused, A = absent

- The draft of the corrigendum was reviewed. During MEC (mandatory editorial coordination), the IEEE-SA demanded that the unchanged text in the corrigendum be deleted. Discussion concluded that IEEE-SA would not bend on this and we will take out the unchanged text.
- Attendees were asked if there were other issues concerning the corrigendum. The words "It is recommended that the arc initiation wire be a fine stranded wire type, such as SIS with the insulating covering removed" will be modified to read "It is recommended that the arc initiation wire be a fine stranded wire type. Wire with ASTM Class K stranding has been found to provide consistent results with regard to arcing duration. Wire with fewer strands may not produce enough ionized gas quickly enough to prevent premature extinction at lower voltages."
- "a metal wire" will be changed to "copper wire measuring" in the two places where it occurs in the first two paragraphs of clause 5.3. This mandates copper, and allows use of multiple wires.

- No other objections were raised.
- Comments raised by Mr. Puckett were discussed.
  - 5.2.3, Page 3, lines 3-6  
Question – If a compartment in LV switchgear designed for fused breakers is tested and a fused breaker is not in the test current path, should the test be performed at 2.3X or 2.16X?

Suggest revising lines 3-6 as follows:

2.3 times the value of the internal arcing short-circuit current for low-voltage metal-enclosed power circuit breaker switchgear ~~using unfused LV power circuit breaker assemblies.~~

2.16 times the value of the internal arcing short-circuit current for low voltage metal-enclosed power circuit breaker switchgear using fused LV circuit breaker assemblies when the circuit breaker is included in the test circuit.

Conclusion – considerable discussion, spirit of comment accepted but language modified.

- 5.2.3, Page 3, lines 3-6 and 5.3, page 4, lines 15-19. Suggest eliminating SIS, requiring copper, and defining stranding more rigorously. This comment handled earlier in meeting.
  - 5.3, Page 4, lines 18 – 19: Wire size #24 is harmonized with IEC. Insulation issue resolved earlier. Intent is to generate enough plasma that the arc will be sustained.
  - 5.4, page 4, lines 20-22: Table B.1 is somewhat tutorial, for the user, and not intended to dictate requirements for internal arcing tests. This is outside the scope of the PAR for the corrigendum.
- The document is now ready for ballot. It will be circulated one last time for WG review and then submitted for ballot.

The meeting adjourned at 9:38AM.

Report submitted by:

M. Wactor, WG Chair